

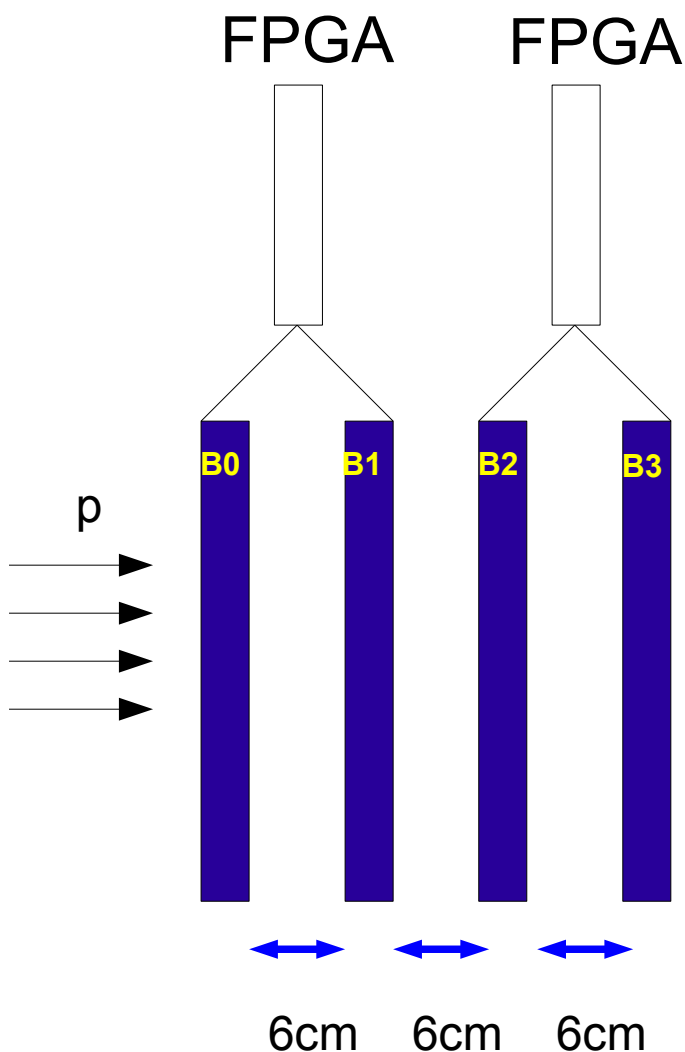
# Jülich Beam Test Results

L. Zotti



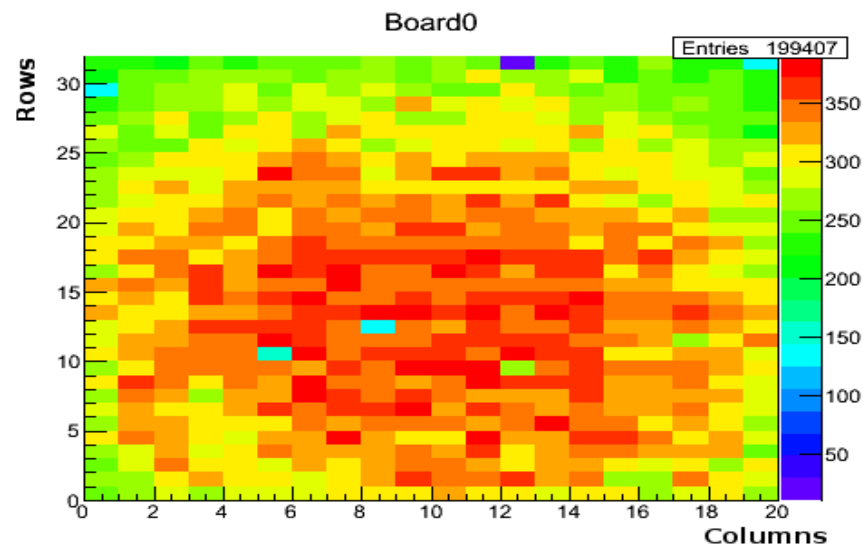
# Jülich Beam Test @ COSY (November 2014)

p@2.9 GeV/c



4 Assemblies:

- Topix4
- Epitaxial Silicon Sensor (2x3.2 mm<sup>2</sup>)



- Clock Frequency Scan
- Theshold Scan
- Bias Scan
- Freeze Scan

# Jülich Beam Test @ COSY

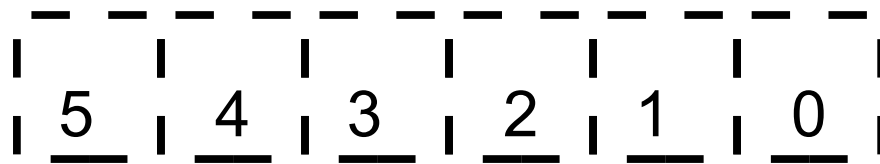
## DAQ & DATA FORMAT

### DAQ - LabView (R.Wheadon)

#### 8 Bytes Long Packet Header with

- Packet Numbers
- # Following Bytes

#### 6 Bytes Event (MSB First)



CHIP ID

- FRAME HEADER
- FRAME DATA
- FRAME IDLE
- FRAME TRAILER

Position	# bits	Data
39:38	2	Header (01 for FH)
37:26	12	Chip address
25:18	8	Frame counter
17:6	12	Not used (set to Hex 5A5)
5:0	6	Error Correction Code

Position	# bits	Data
39:38	2	Header (11 for data)
37:24	14	Pixel address
23:12	12	Leading edge time stamp
11:0	12	Trailing edge time stamp

Position	# bits	Data
39:38	2	Header (00 for idle)
37:0	16	Idle patter (Hex 3A55AA55AA)

Position	# bits	Data
39:38	2	Header (10 for TH)
37:22	16	Number of events
21:6	16	Frame CRC
5:0	6	Error Correction Code

Dummy Events: LE or TE = 2730 or 2729

# Jülich Beam Test @ COSY

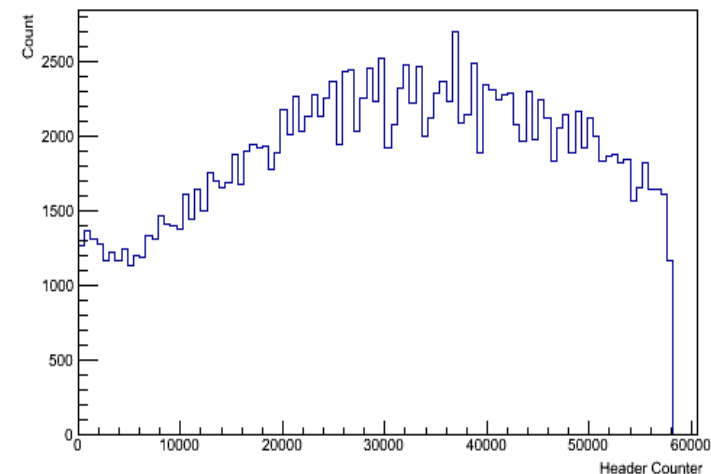
## FACING TIMESTAMP....

**TIMESTAMP = 8bit (FRAME\_COUNTER) + 12bit (LEADING\_EDGE)**  
**.....but @ 50 MHz: 20 ms → with a spill of ~20s: 1000 reset**  
**@ 160 MHz: 6.25 ms → with a spill of ~20s: 3200 reset**

**The standard timestamp matching procedure is not able at the moment to find time match....**

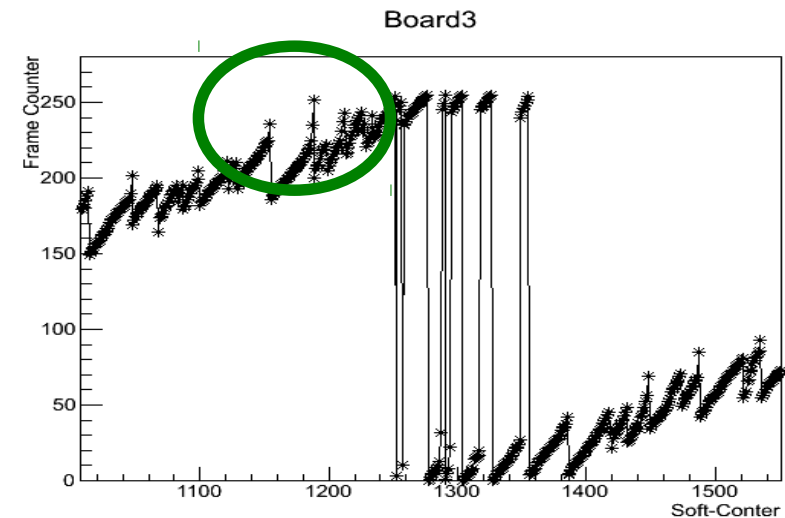
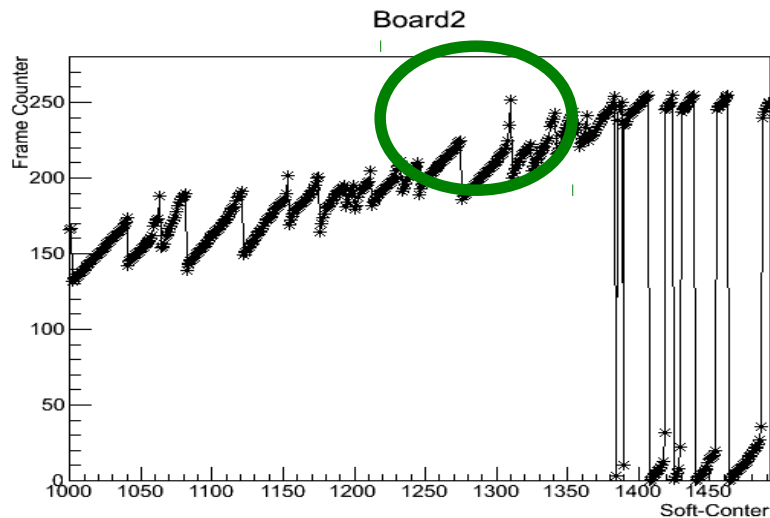
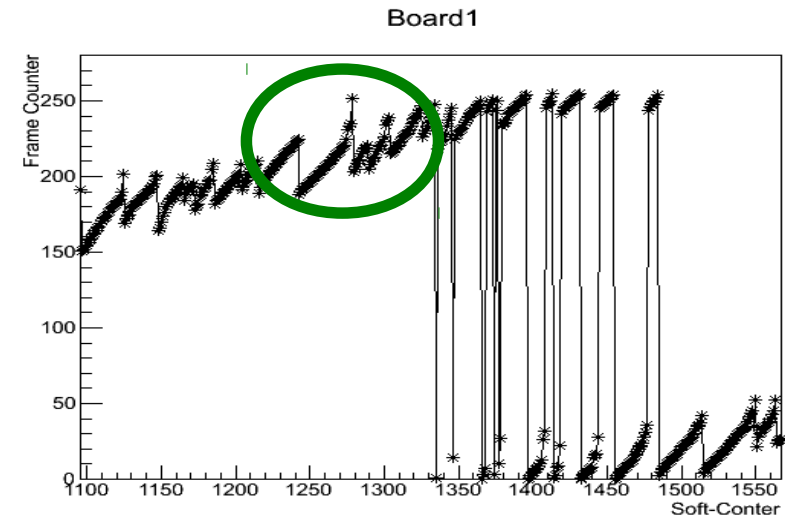
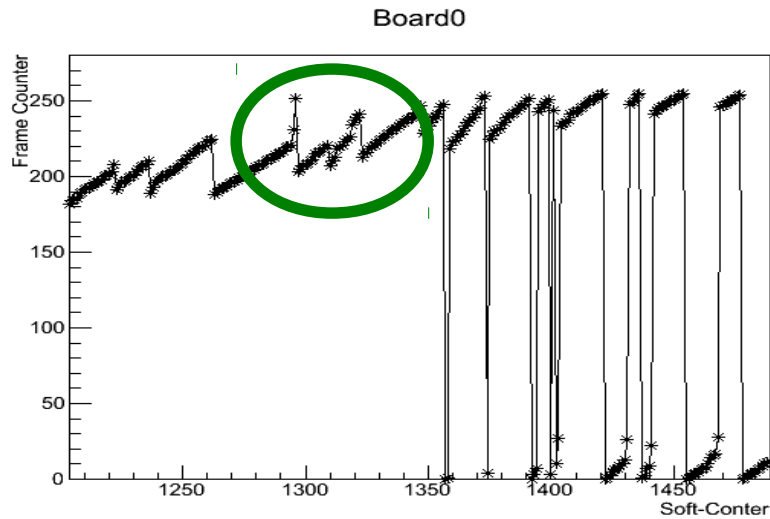
- **An additional 7bit counter was added, but has not been used in the timestamp matching procedure for alignment dubts...**
- **A software counter, labeling the header frame, was added but since empty frame are filtered out, no time reference is present at the moment...**

- Debug analysis of the acquisition performance
- Comparison of the frame counter behaviour



# Jülich Beam Test @ COSY

## New TimeStamp Matching Procedure

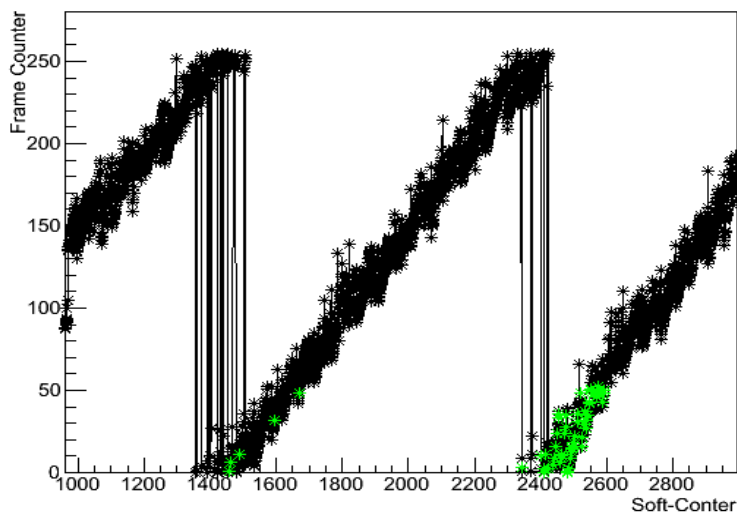


A new code was developed to find match between data set with the same frame counter taking into account disalignment between header counter

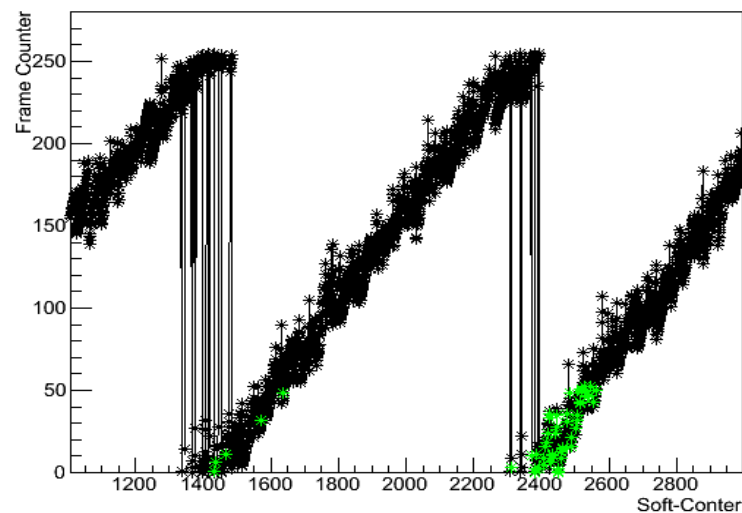
# Jülich Beam Test @ COSY

## New TimeStamp Matching Procedure

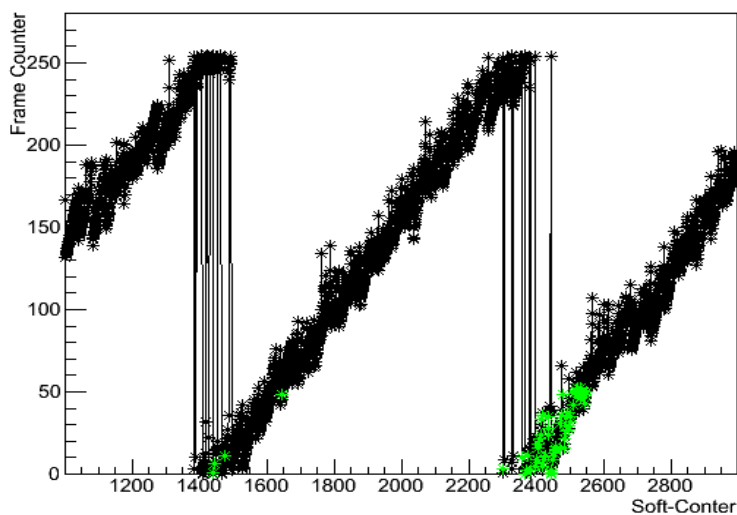
Board0



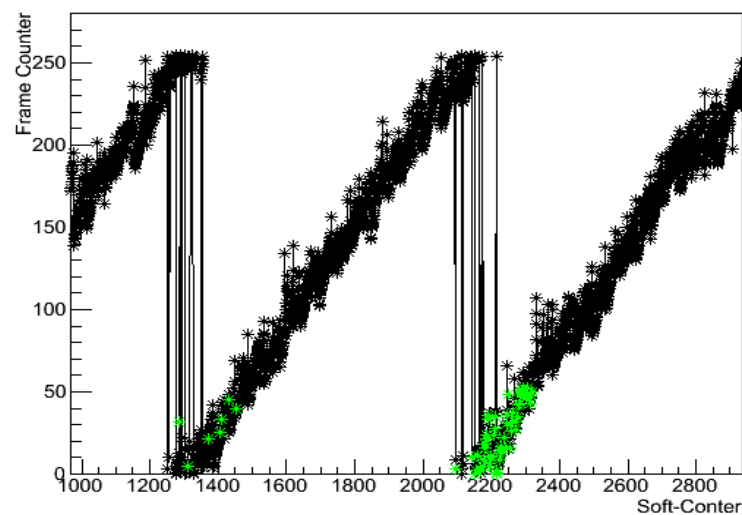
Board1



Board2



Board3



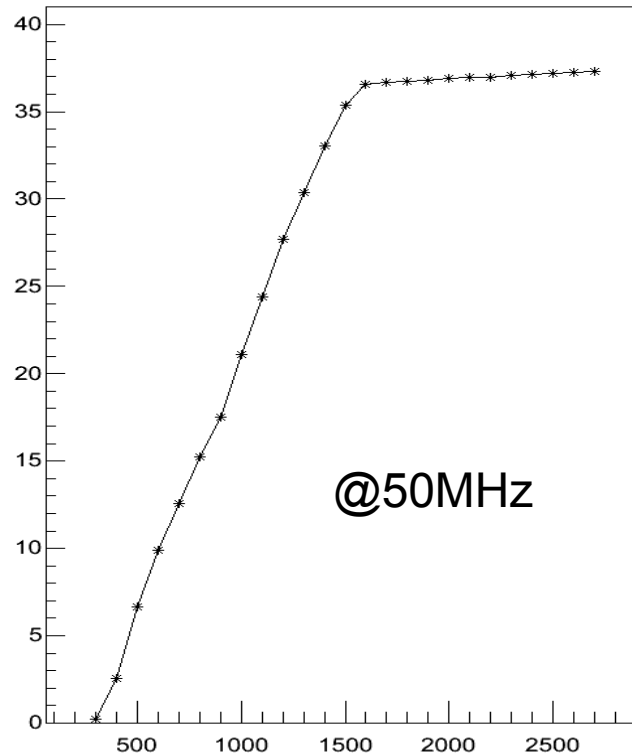
# Jülich Beam Test @ COSY

## New TimeStamp Matching Procedure

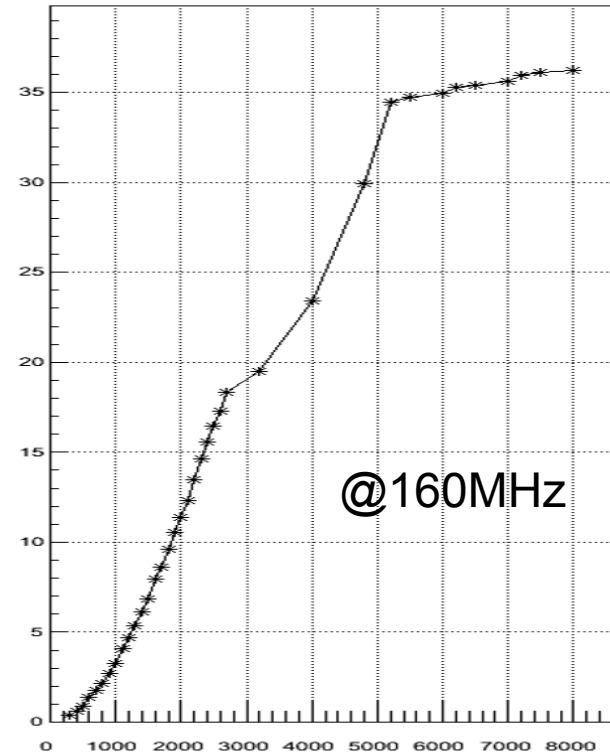
The new timestamp matching procedure should take into account different possible disalignment between boards:

- Clock Range: clock synchronization, comparator delay
- Header Counter disalignment

$\Delta$  Header Scan with +/-2clock



$\Delta$  Header Scan with +/-7clock



# Jülich Beam Test @ COSY

## New TimeStamp Matching Procedure

@50MHz

- Track Selection +/- 2 clock cycle (40ns)
- Header Delta 1600
- Cluster Finding +/- 2\*5 clock cycle (200ns)

@160MHz

- Track Selection +/- 7 clock cycle (~43ns)
- Header Delta 5200
- Cluster Finding +/- 7\*5 clock cycle (200ns)

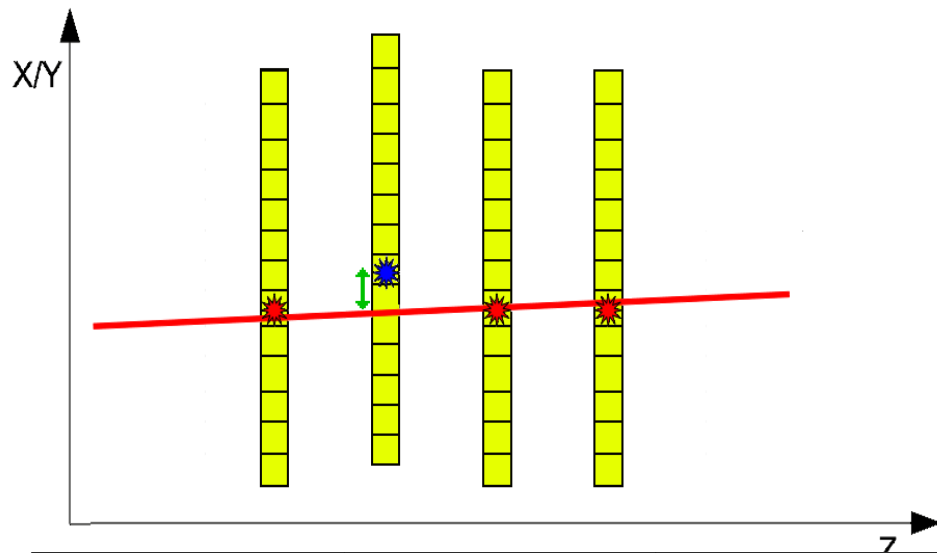


# Jülich Beam Test @ COSY

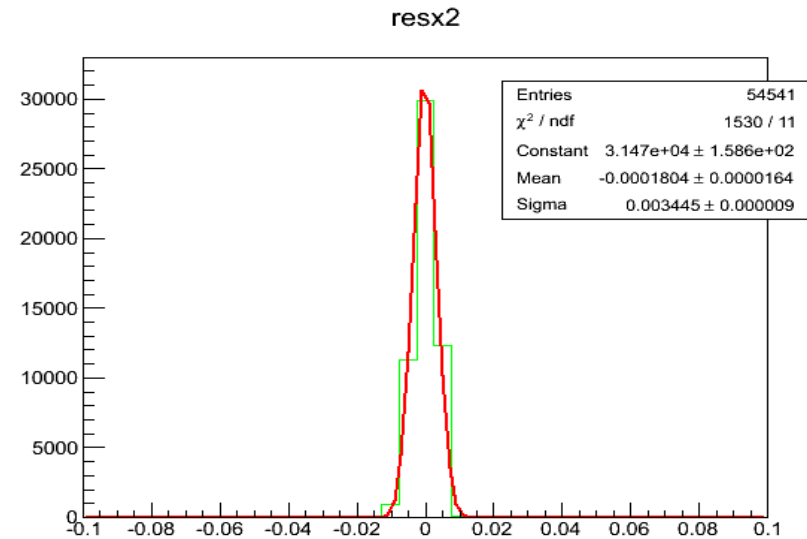
## Alignment

Alignment performed on the 50MHz data set.

Residual method: with one fixed board (either B3 and B0 have been evaluated giving similar results)



Board	$\Delta x$ [ $\mu\text{m}$ ]	$\Delta y$ [ $\mu\text{m}$ ]
0	56	50
1	36	32
2	31	31
3	52	50

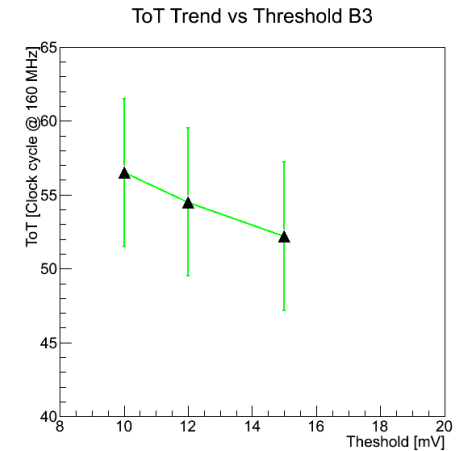
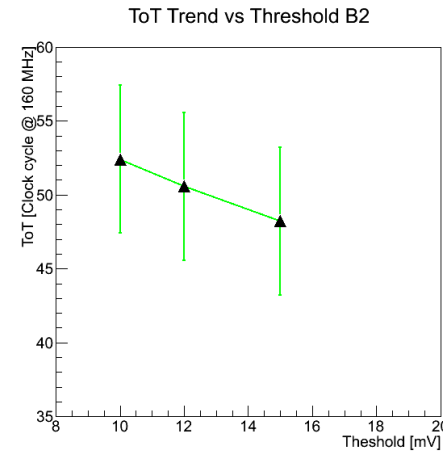
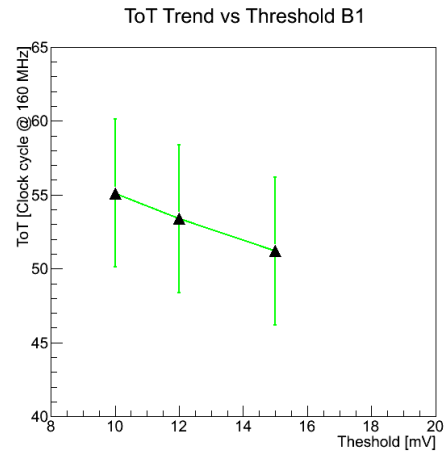
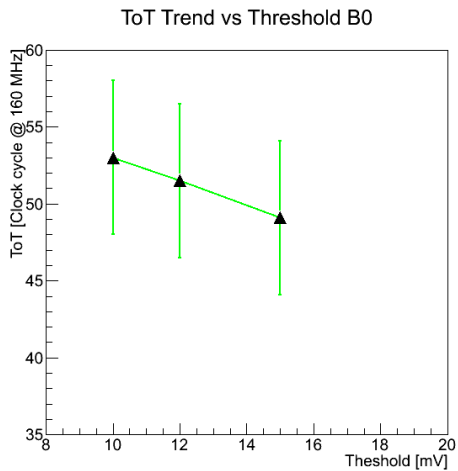


$$\sigma_{\text{track}} = \frac{\sqrt[4]{\sigma_0 * \sigma_1 * \sigma_2 * \sigma_3}}{\sqrt{4}}$$

$$\sigma_x = \sigma_y \simeq 20\mu\text{m}$$

# Jülich Beam Test @ COSY

## Threshold Scan



### Analog Gain [mV/fC]

B0	B1	B2	B3
79 ± 10	88 ± 11	91 ± 11	85 ± 15

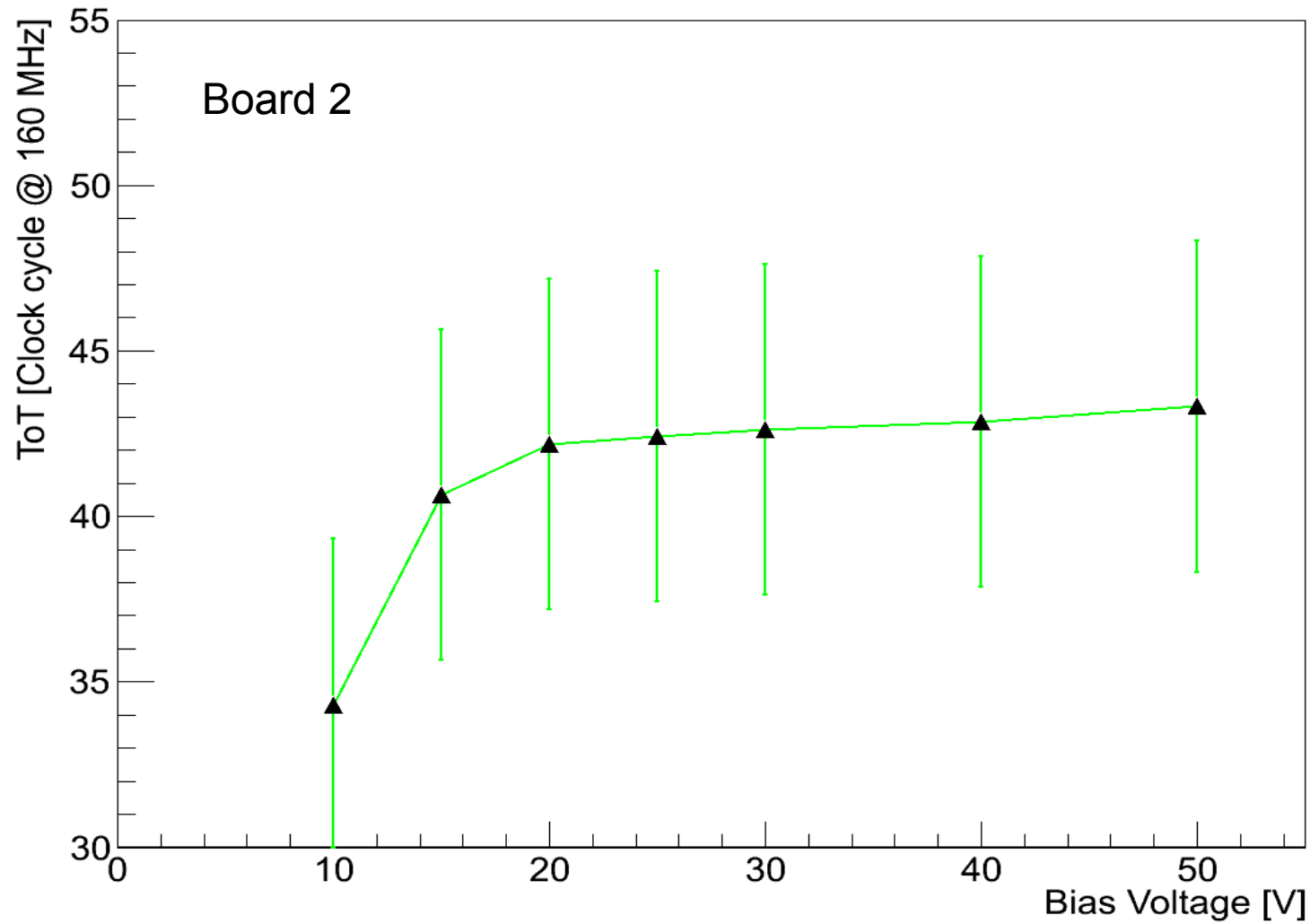
by Olave  
Jonhatan

### Voltage Threshold [e-]

Vth [mV]	Voltage Threshold [e-]			
	B0	B1	B2	B3
10	791 ± 100	710 ± 89	687 ± 83	735 ± 130
12	949 ± 120	852 ± 107	824 ± 100	882 ± 156
15	1187 ± 150	1065 ± 133	1030 ± 125	1103 ± 195
20	1582 ± 200	1420 ± 178	1374 ± 166	1471 ± 260
22	1741 ± 220	1563 ± 195	1511 ± 183	1618 ± 285

# Jülich Beam Test @ COSY

## Bias Scan



# Conclusions

## DONE:

- new timestamp matching procedure developed to face the absence of time reference
- offline alignment performed
- analysis of different scan data sets

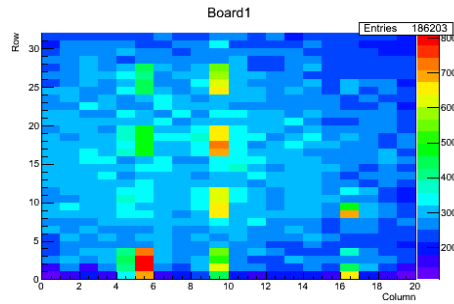
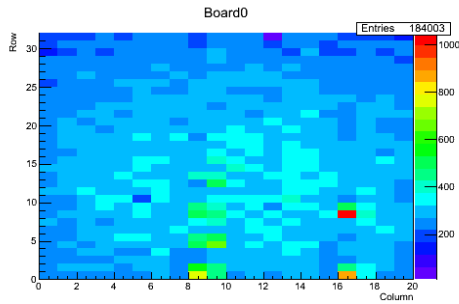
## WORK IN PROGRESS:

- Efficiency evaluation as a function of Bias and Threshold Scan
- Evaluation of the ToT in term of electrons

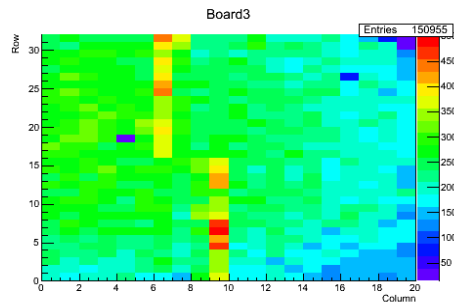
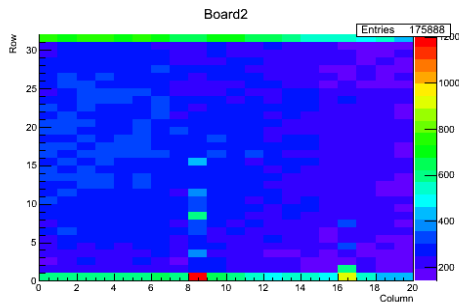
# BACKUP SLIDES

# Julich Beam Test @ COSY

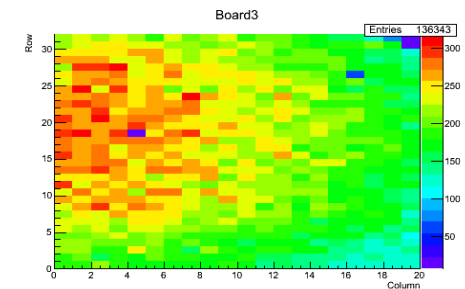
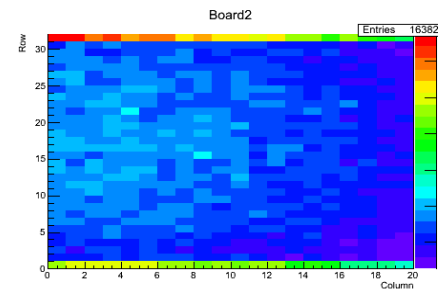
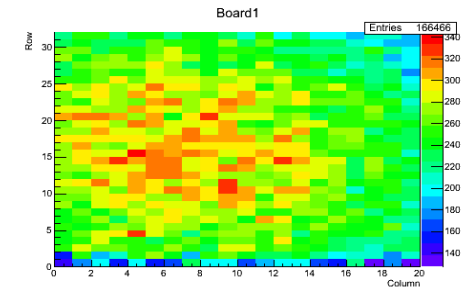
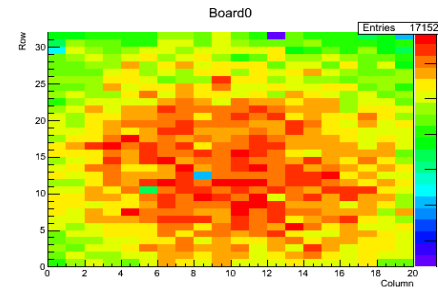
## HIT MAPS



**@ 160 MHz**  
**Rate  $14 \cdot 10^3$  (~22hit per pixel/s)**  
**50% of dummy**

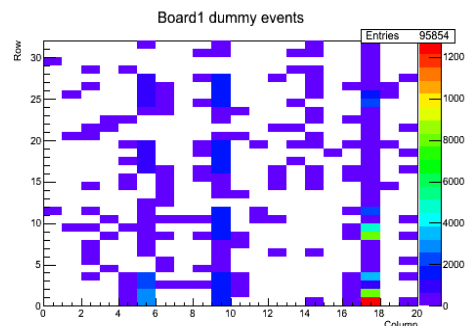
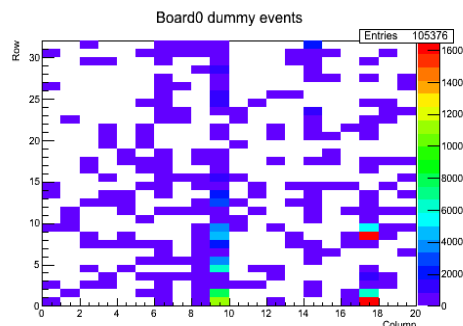


**@ 50 MHz**  
**Rate  $9 \cdot 10^3$  (~14hit per pixel/s)**  
**8% of dummy**

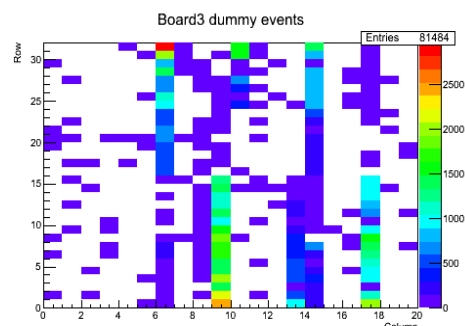
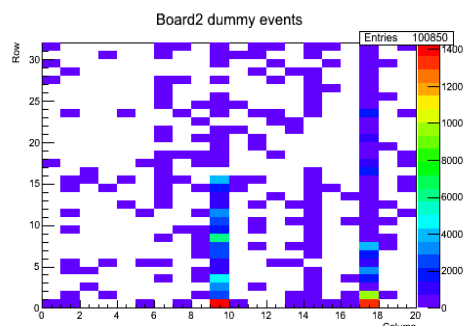


# Julich Beam Test @ COSY

## DUMMY EVENTS



**@ 160 MHz**  
**Rate  $14 \cdot 10^3$  (~22hit per pixel/s)**  
**50% of dummy**



**@ 50 MHz**  
**Rate  $9 \cdot 10^3$  (~14hit per pixel/s)**  
**8% of dummy**

